

TOSHIBA Transistor Silicon NPN Epitaxial Type

TPC6501

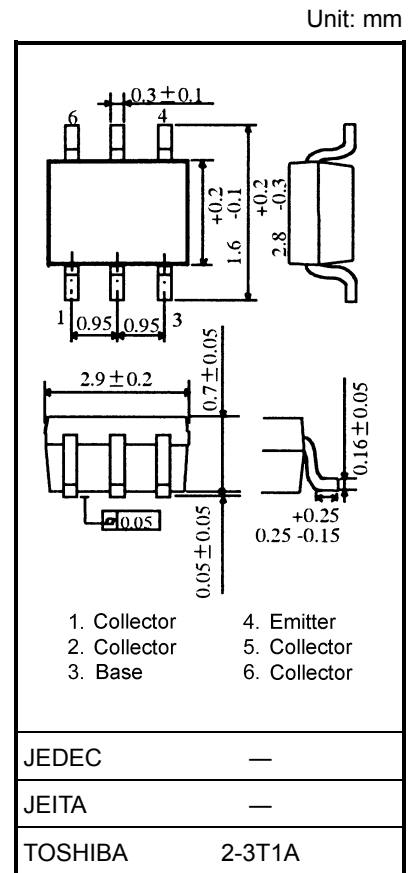
High-Speed Switching Applications
 DC-DC Converter Applications
 Strobe Applications

- High DC current gain: $h_{FE} = 400$ to 1000 ($I_C = 0.2$ A)
- Low collector-emitter saturation voltage: $V_{CE(sat)} = 0.12$ V (max)
- High-speed switching: $t_f = 25$ ns (typ.)

Maximum Ratings ($T_a = 25^\circ\text{C}$)

Characteristics		Symbol	Rating	Unit
Collector-base voltage		V_{CBO}	20	V
Collector-emitter voltage		V_{CEO}	10	V
Emitter-base voltage		V_{EBO}	7	V
Collector current	DC	I_C	2.0	A
	Pulse	I_{CP}	3.5	
Base current		I_B	200	mA
Collector power dissipation	DC	P_C	0.8	W
	$t = 10$ s	(Note)	1.6	
Junction temperature		T_j	150	$^\circ\text{C}$
Storage temperature range		T_{stg}	-55 to 150	$^\circ\text{C}$

Note: Mounted on FR4 board (glass epoxy, 1.6 mm thick, Cu area: 645 mm²)



Electrical Characteristics ($T_a = 25^\circ\text{C}$)

Characteristics		Symbol	Test Condition	Min	Typ.	Max	Unit
Collector cut-off current		I_{CBO}	$V_{CB} = 20$ V, $I_E = 0$	—	—	100	nA
Emitter cut-off current		I_{EBO}	$V_{EB} = 7$ V, $I_C = 0$	—	—	100	nA
Collector-emitter breakdown voltage		$V_{(BR)CEO}$	$I_C = 10$ mA, $I_B = 0$	10	—	—	V
DC current gain		$h_{FE(1)}$	$V_{CE} = 2$ V, $I_C = 0.2$ A	400	—	1000	
		$h_{FE(2)}$	$V_{CE} = 2$ V, $I_C = 0.6$ A	200	—	—	
Collector-emitter saturation voltage		$V_{CE(sat)}$	$I_C = 0.6$ A, $I_B = 12$ mA	—	—	0.12	V
Base-emitter saturation voltage		$V_{BE(sat)}$	$I_C = 0.6$ A, $I_B = 12$ mA	—	—	1.10	V
Switching time	Rise time	t_r	See Figure 1 circuit diagram.	—	60	—	ns
	Storage time	t_{stg}	$V_{CC} \approx 6$ V, $R_L = 10 \Omega$	—	215	—	
	Fall time	t_f	$I_{B1} = -I_{B2} = 12$ mA	—	25	—	

Circuit Configuration

Marking

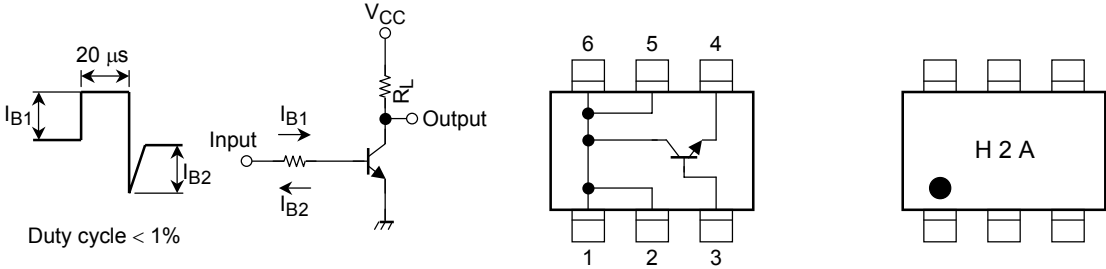
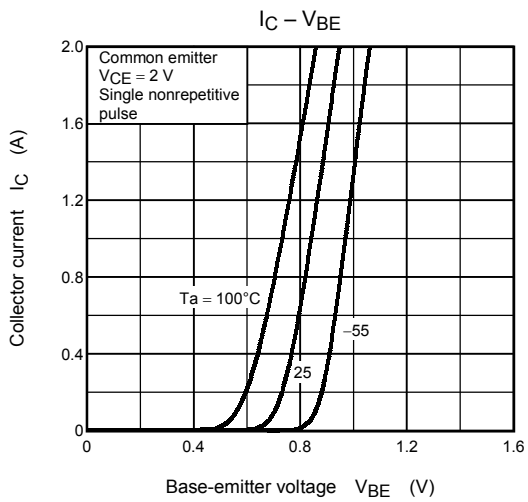
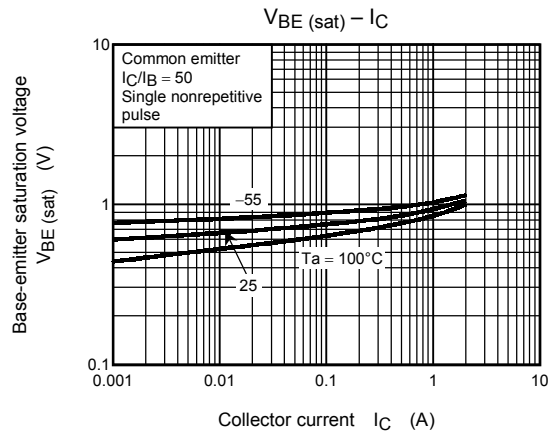
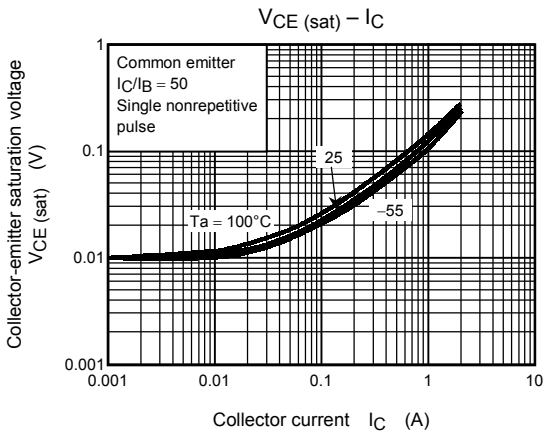
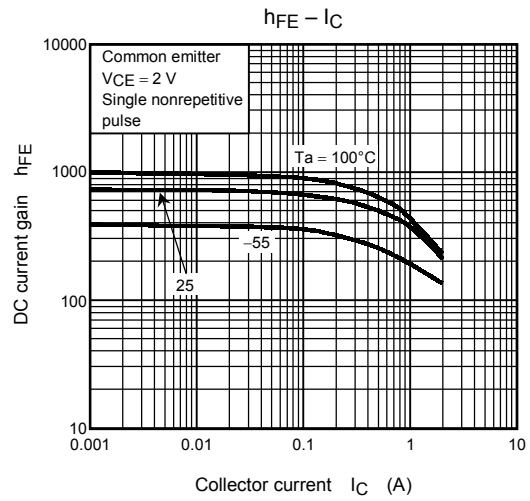
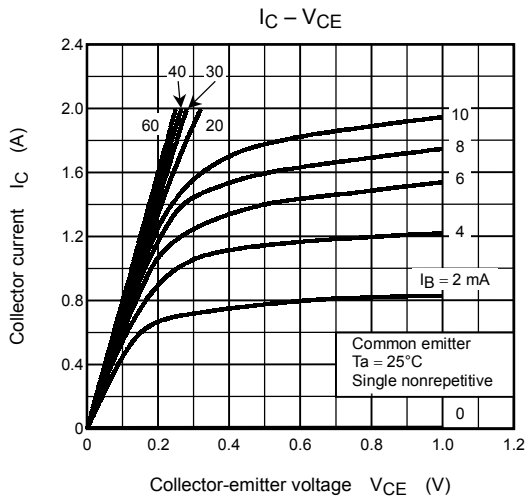
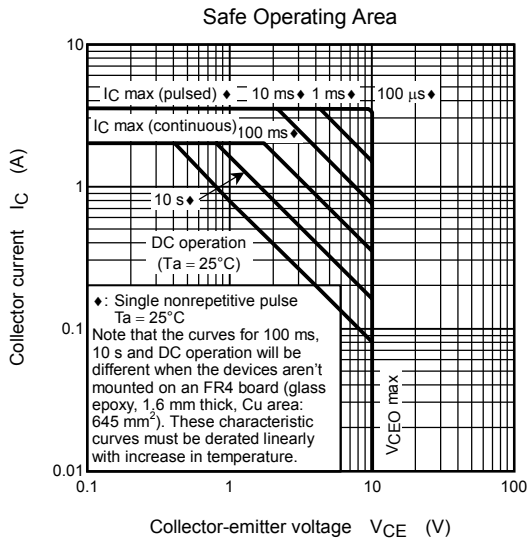
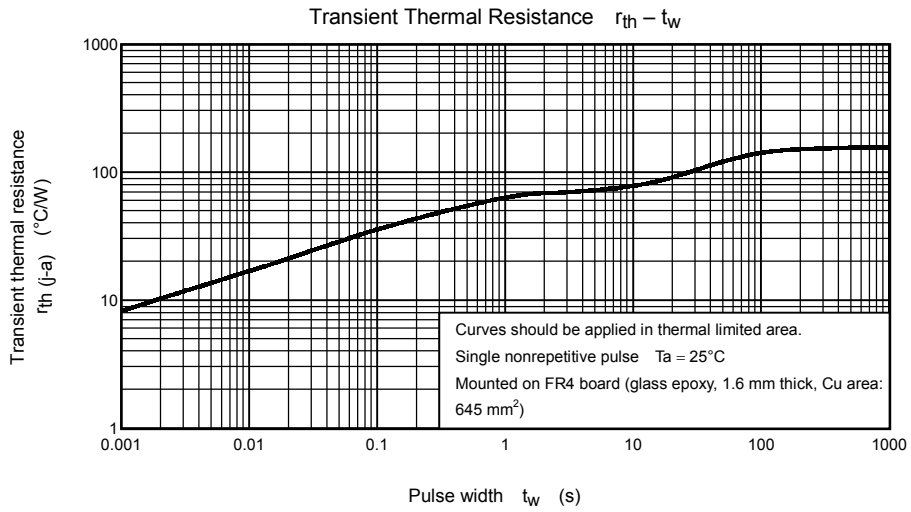


Figure 1 Switching Time Test Circuit & Timing Chart





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